

## Microprocessor Lab Manual With Theory

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The paper will look at the systems for direct shear tests, sample preparation, the stages of the test, some of the theory behind direct shear tests and also automation of the test process. It is recommended that this support document is read in conjunction with the glossary of terms that can be found in the 'Support' section of VJ Tech's ...

### An Introduction to Direct Shear Testing - VJ Tech

\\$)\begingroup\\$ If you do this with real voltage sources (power supplies) the end result will depend on the details. Some power supplies are incapable of sinking current to maintain their output voltage. For that type of supply, when you hook them up in parallel, whichever one is set to a higher voltage wins.

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